

IEEE Recommended Practice for Voltage-Endurance Testing of Form-Wound Bars and Coils

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Sponsored by the
Voltage Endurance Technical Committee of the
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IEEE Std 1043-1989



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Sponsor
Voltage Endurance Technical Committee
of the
IEEE Dielectrics and Electrical Insulation Society

Approved August 17, 1989
IEEE Standards Board

Abstract: IEEE Std 1043-1989, *IEEE Recommended Practice for Voltage-Endurance Testing of Form-Wound Bars and Coils*, describes the procedure for determining the ability of a rotating machine stator insulation system to withstand operation at high voltages and temperatures. The voltage-endurance test enables the design and manufacturing process of the stator insulation system to be evaluated.

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Foreword

(This Foreword is not a part of IEEE Std 1043-1989, IEEE Recommended Practice for Voltage-Endurance Testing of Form-Wound Bars and Coils.)

This recommended practice is the first version of a document to standardize a test procedure to evaluate the voltage-endurance capabilities of form-wound bars and coils used in high-voltage motors and generators. This recommended practice is based on over 30 years of experience with such testing by machine manufacturers and users. There is no attempt to set pass or fail test criteria in this document.

This recommended practice was prepared by a joint working group of the Dielectric and Electrical Insulation Society's Voltage Endurance Technical Committee and the Insulation Subcommittee of the Rotating Machinery Committee of the Power Engineering Society. The working group members are:

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A. I. Bennett
E. M. Fort
B. K. Gupta

T. B. Jenkins
L. Klataske
T. J. Lorenz
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